Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	***
10/762,364	MAITLAND ET AL.	
Examiner	Art Unit	
Ellen C. Tran	2134	

	0545					
	SEARCHED					
Class	Subclass	Date	Examiner			
713	150	6/23/2007	ET			
380	265, 259	6/23/2007	ET			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
		<u>, </u>			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
INVENTOR SEARCH - PALM	6/23/2007	ΕT	
NPL - IEEE XPLORE	6/23/2007	ET	
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	6/23/2007	ET	
ALL CLAIMS WERE REVIEWED FOR POSSIBLE 101 REJECTIONS	6/23/2007	ET	
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